

ERRATUM

Erratum: “SiO Mass Spectrometry and Si-2p
Photoemission Spectroscopy for the Study of
Oxidation Reaction Dynamics of Si(001) Surface
by Supersonic O₂ Molecular Beams under 1000 K”

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Erratum: “SiO Mass Spectrometry and Si-2p Photoemission Spectroscopy for the Study of Oxidation Reaction Dynamics of Si(001) Surface by Supersonic O₂ Molecular Beams under 1000 K” [Jpn. J. Appl. Phys. **42, 4671 (2003)]**

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We have performed experiments on surface chemical reactions using a supersonic O₂ molecular beam. Translational kinetic energy values of the supersonic O₂ molecular beams have been estimated by calculations. We have noticed a mistake in the calculations. We had calculated the translational kinetic energy with gas constant $R = 1.134 \times 10^{-4}$ eV/K. However, $R = 8.617 \times 10^{-5}$ eV/K is correct. Consequently, the correct translational kinetic energy values can be obtained by multiplying those in the published article by a factor of 0.76. Even if they are corrected, conclusions and the points of arguments are as they are except the translational kinetic energy values themselves. The corrected values are tabulated in the following table.

		Value in the article	Corrected value
p. 4671	Abstract 2nd line	0.7 eV, 2.2 eV, 3.3 eV	0.53 eV, 1.7 eV, 2.5 eV
	Left column 27th line	3 eV	2.3 eV
	Left column 30th line	1.0 eV, 2.6 eV	0.76 eV, 2.0 eV
	Right column 32nd line	0.7 eV, 2.2 eV	0.53 eV, 1.7 eV
	Right column 33rd line	3.3 eV	2.5 eV
p. 4672	Left column 31st line	3.0 eV	2.3 eV
	Left column 35th line	3.0 eV	2.3 eV
	Left column 36th line	3 eV	2.3 eV
p. 4673	Fig. 2	0.7 eV, 2.2 eV, 3.3 eV	0.53 eV, 1.7 eV, 2.5 eV
	Left column 5th line	0.7 eV, 2.2 eV, 3.3 eV	0.53 eV, 1.7 eV, 2.5 eV
	Left column 22nd line	2.2 eV	1.7 eV
	Left column 23rd line	0.7 eV	0.53 eV
	Left column 29th line	1 eV, 3 eV	0.76 eV, 2.3 eV
	Left column 30th line	3.3 eV	2.5 eV
	Left column 31st line	2.2 eV	1.7 eV
p. 4674	Fig. 3	0.8 eV, 1.2 eV, 1.5 eV, 2.0 eV, 2.5 eV, 2.7 eV, 3.0 eV	0.61 eV, 0.91 eV, 1.1 eV, 1.5 eV, 1.9 eV, 2.1 eV, 2.3 eV
	Left column 11th line	0.8 eV	0.61 eV
	Left column 15th line	0.7 eV	0.53 eV
	Left column 19th line	1.5 eV	1.1 eV
	Right column 7th line	0.7 eV, 2.2 eV, 3.3 eV	0.53 eV, 1.7 eV, 2.5 eV